

April 2013

FQD3N60C / FQU3N60C N-Channel QFET® MOSFET 600 V, 2.4 A, 3.4 Ω

Features

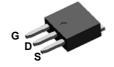
- 2.4 A, 600 V, $R_{DS(on)}$ = 3.4 Ω (Max.) @ V_{GS} = 10 V, I_D = 1.2 A
- Low Gate Charge (Typ. 10.5 nC)
- Low Crss (Typ. 5 pF)
- · 100% Avalanche Tested

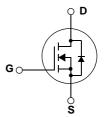
Description

I-PAK

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballas







D-PAK

Absolute Maximum Ratings

Symbol	Parameter		FQD3N60C / FQU3N60C	Unit	
V _{DSS}	Drain-Source Voltage		600	V	
I _D	Drain Current - Continuous (T _C = 25°C)		2.4	Α	
	- Continuous (T _C = 100°C)		1.5	Α	
I _{DM}	Drain Current - Pulsed	(Note 1)	9.6	Α	
V _{GSS}	Gate-Source Voltage		± 30	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	150	mJ	
I _{AR}	Avalanche Current	(Note 1)	2.4	Α	
E _{AR}	Repetitive Avalanche Energy	(Note 1)	5.0	mJ	
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.5	V/ns	
P_{D}	Power Dissipation (T _C = 25°C)		50	W	
	- Derate above 25°C	0.4	W/°C		
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C	
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

Thermal Characteristics

Symbol	Parameter	FQD3N60C / FQU3N60C	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	2.5	°C/W
$R_{\theta J A^*}$	Thermal Resistance, Junction-to-Ambient*	50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	110	°C/W

^{*} When mounted on the minimum pad size recommended (PCB Mount)

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQD3N60C	FQD3N60CTM	D-PAK	380mm	16mm	2500
FQD3N60C	FQD3N60CTF	D-PAK	380mm	16mm	2000
FQU3N60C	FQU3N60CTU	I-PAK	-	-	75

Electrical Characteristics $T_C = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Charac	teristics					
BV _{DSS}	Drain-Source Breakdown Voltage	V_{GS} = 0 V, I_{D} = 250 μ A	600			V
$\Delta BV_{DSS}/$ ΔT_J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.6		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 600 V, V _{GS} = 0 V			1	μА
		V _{DS} = 480 V, T _C = 125°C			10	μА
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Charact	eristics			•		
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 1.2 A		2.8	3.4	Ω
g _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 1.2 A (Note 4)		3.5		S
Dynamic Cl	haracteristics					
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V,		435	565	pF
C _{oss}	Output Capacitance	f = 1.0 MHz		45	60	pF
C _{rss}	Reverse Transfer Capacitance			5	8	pF
Switching C	Characteristics					
t _{d(on)}	Turn-On Delay Time	V _{DD} = 300 V, I _D = 3A,		12	34	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		30	70	ns
t _{d(off)}	Turn-Off Delay Time			35	80	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		35	80	ns
Q _g	Total Gate Charge	V _{DS} = 480 V, I _D = 3A,		10.5	14	nC
Q_{gs}	Gate-Source Charge	V _{GS} = 10 V		2.1		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)		4.5		nC
Drain-Source	ce Diode Characteristics and Maximum Ratings					
I _S	Maximum Continuous Drain-Source Diode Forward Current				3	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				12	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 2.4 A			1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 3 A,		260		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		1.6		μС

NOTES

^{1.} Repetitive Rating : Pulse width limited by maximum junction temperature

^{2.} L = 47mH, I $_{AS}$ = 2.4A, V $_{DD}$ = 50V, R $_{G}$ = 25 Ω , Starting T $_{J}$ = 25°C

^{3.} $I_{SD} \le 3A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting T_J = 25°C

^{4.} Pulse Test : Pulse width $\leq 300 \mu \text{s}, \ \text{Duty cycle} \leq 2\%$

^{5.} Essentially independent of operating temperature

Typical Performance Characteristics

Figure 1. On-Region Characteristics

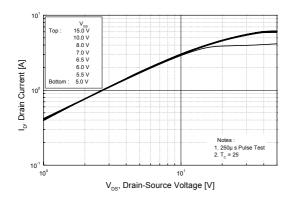


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

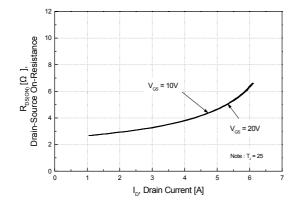


Figure 5. Capacitance Characteristics

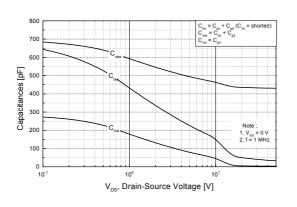


Figure 2. Transfer Characteristics

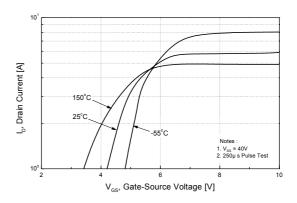


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

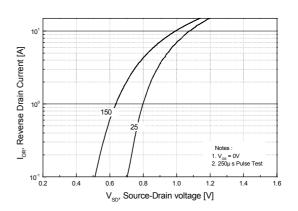
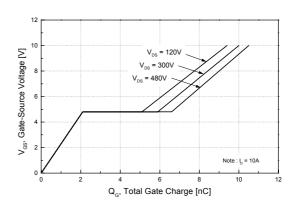


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

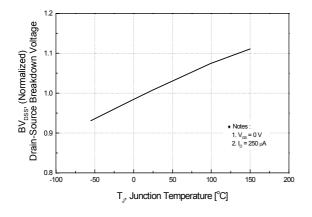


Figure 8. On-Resistance Variation vs. Temperature

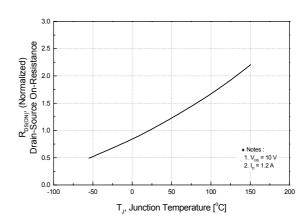


Figure 9. Maximum Safe Operating Area

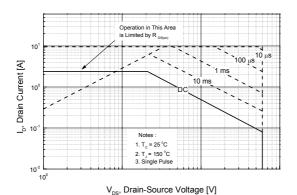


Figure 10. Maximum Drain Current vs. Case Temperature

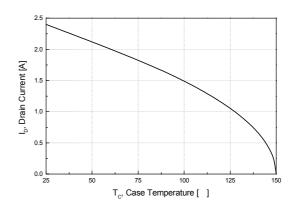
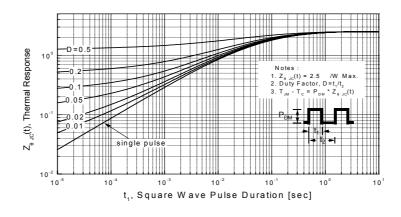
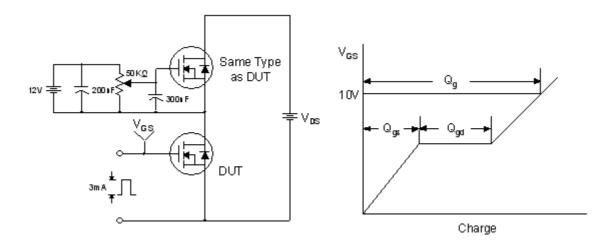


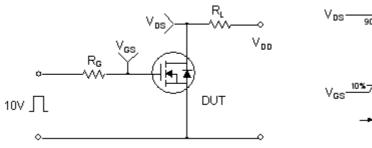
Figure 11. Transient Thermal Response Curve

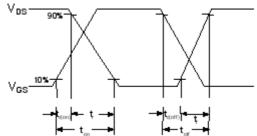


Gate Charge Test Circuit & Waveform

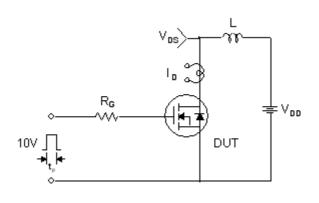


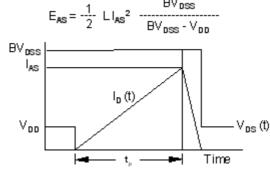
Resistive Switching Test Circuit & Waveforms



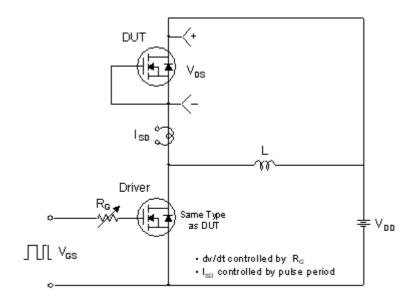


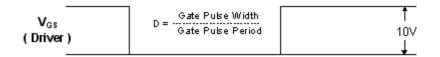
Unclamped Inductive Switching Test Circuit & Waveforms

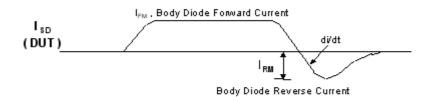


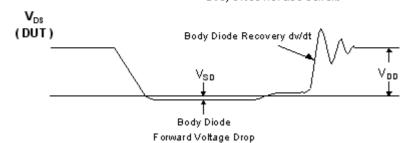


Peak Diode Recovery dv/dt Test Circuit & Waveforms



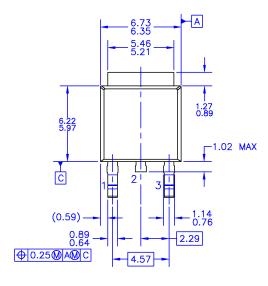


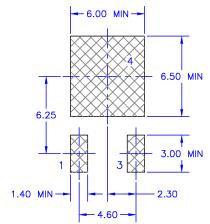




Mechanical Dimensions

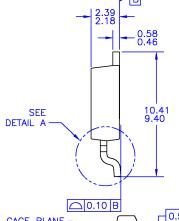
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4.32 MIN NOTE D 5.21 MIN



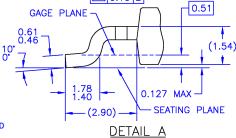


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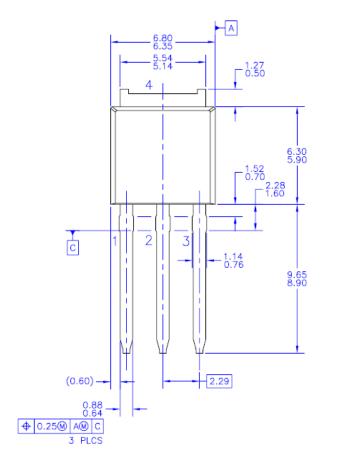


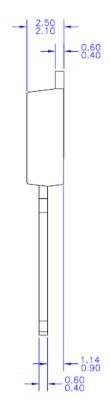
(ROTATED -90°) SCALE: 12X

Dimensions in Millimeters

Mechanical Dimensions

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